

Search Notes

Application/Control No.

10/681,517

Examiner

Hai L. Nguyen

Applicant(s)/Patent under
Reexamination

LO ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
331	16-18, 10, 11, 1A, 25, DIG.2	3/31/2005	HLN
327	147, 148		
	150, 156		
	157, 159		
	162, 163		
375	373-376		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	4/2/2005	HLN